



Approved Method: **Measuring  
Luminous Flux and  
Color Maintenance  
of LED Packages,  
Arrays and Modules**

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Luminous Flux and Color Maintenance  
of LED Packages, Arrays and Modules**

**Publication of this Committee report  
has been approved by IES.  
Suggestions for revisions  
should be directed to IES**

**Prepared by:  
The Solid-State Lighting Subcommittee  
of the IES Testing Procedures Committee**

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